Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
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MAUPIN, PATRICK EVAN

Examiner

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SEARCHED

Class	Subclass	Date	Examiner
375	295, 377, 222, 220	2/26/2007	LF
370	276	2/26/2007	LF
455	39, 73, 91	2/26/2007	LF

SEARCH NOTES

Search Notes	Date	Examiner
Consulted with SPE David Payne in regards to the patentability of claim 1.	2/27/2007	LF
Checked for Double patenting.	2/26/2007	LF
Consulted with SPE David Payne in regards to the amendments.	5/18/2007	· LF
Consulted with SPE David Payne in regards to the amendments.	7/18/2007	LF

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
375	295	7/18/2007	LF
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